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Application/Control No.	Applicant(s)/Patent under Reexamination
10/797,824	CHAO ET AL.
Examiner	Art Unit
Charles R. Kasenge	2125

	SEARCHED				
Class	Subclass	Date	Examiner		
700	99	7/7/2005	СК		
	100				
	101				
	112				
	113				
	121				
438	8				
	14				

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
700	121	1/10/2006	СК
	112		
	ttached ce Search	1/10/2006	ск

SEARCH NO (INCLUDING SEARCH		)
	DATE	EXMR
Updated EAST; terms: ((replac\$3 (back adj up) backup substitut\$3) near2 (wafer workpiece substrate)) same (metal adj layer\$3)	1/10/2006	СК
Inventor and Assignee Search	1/10/2006	CK